

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/567,327 ISHIKAWA ET AL.	
		Examiner	Art Unit	Page 1 of 1 Khanh T. Nguyen 1796

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,790,819	09-2004	Trinh et al.	510/287
*	B	US-7,052,681	05-2006	Ferrari, Veronique	424/64
*	C	US-2002/0131947	09-2002	Nakanishi, Tetsuo	424/70.12
*	D	US-2002/0159964	10-2002	Nakanishi et al.	424/70.12
*	E	US-5,035,832	07-1991	Takamura et al.	510/405
*	F	US-3,414,604	12-1968	PEPE ENRICO J; et. al.	556/440
*	G	US-2002/0058129	05-2002	Idehara et al.	428/195
*	H	US-2003/0035748	02-2003	TRINH et al.	422/5
*	I	US-2002/0011584	01-2002	Uchiyama et al.	252/8.91
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.